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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
09/845,477	04/30/2001	Chine-Gie Lou	TS2000499	2319		
28112 7	590 12/03/2002					
GEORGE O. SAILE & ASSOCIATES			EXAM	EXAMINER		
28 DAVIS AVENUE POUGHKEEPSIE, NY 12603			GUERRERO	, MARIA F		
			ART UNIT	PAPER NUMBER		
		2822				

DATE MAILED: 12/03/2002

Please find below and/or attached an Office communication concerning this application or proceeding.

20		Applicatio	n No.	Applicant(s)	
•		09/845,47	7	LOU, CHINE-GIE	
	Office Action Summary	Examiner		Art Unit	
		Maria Gue	rrero	2822	
Period fo A SH	ORTENED STATUTORY PERIOD FOR	REPLY IS SET TO		·	
- Exter after - If the - If NO - Failur - Any n	MAILING DATE OF THIS COMMUNICA nsions of time may be available under the provisions of 37 SIX (6) MONTHS from the mailing date of this communic period for reply specified above is less than thirty (30) da period for reply is specified above, the maximum statutor re to reply within the set or extended period for reply will, eply received by the Office later than three months after to depart term adjustment. See 37 CFR 1.704(b).	7 CFR 1.136(a). In no ever ation. tys, a reply within the statury ry period will apply and will by statute, cause the appli	tory minimum of thirty (30) day expire SIX (6) MONTHS from cation to become ABANDONE	s will be considered timely. the mailing date of this communic	ation.
1)🖂	Responsive to communication(s) filed	on <u>23 September 2</u>	<u> 2002</u> .		
2a)⊠	This action is FINAL . 2b)	☐ This action is r	non-final.		
3)□ Dispositi	Since this application is in condition for closed in accordance with the practice on of Claims	r allowance except under <i>Ex parte</i> Qu	for formal matters, pr ayle, 1935 C.D. 11, 4	osecution as to the mer 53 O.G. 213.	its is
4)⊠	Claim(s) 13-24 is/are pending in the ap	plication.			
4	4a) Of the above claim(s) is/are w	vithdrawn from con	sideration.		
5)	Claim(s) is/are allowed.				
6)⊠	Claim(s) <u>13-24</u> is/are rejected.				
7)	Claim(s) is/are objected to.				
8)[Claim(s) are subject to restriction	and/or election re	quirement.		
Application	on Papers				
9)∐ Т	The specification is objected to by the Ex	caminer.			
10)∐ T	he drawing(s) filed on is/are: a)[accepted or b)	bjected to by the Exar	niner.	
	Applicant may not request that any objection	on to the drawing(s) b	e held in abeyance. Se	ee 37 CFR 1.85(a).	
11)∐ T	he proposed drawing correction filed on	is: a)∏ ap	proved b) disappro	ved by the Examiner.	
	If approved, corrected drawings are require	ed in reply to this Offic	ce action.		
12)□ T	he oath or declaration is objected to by	the Examiner.			
ri rity u	nder 35 U.S.C. §§ 119 and 120				
13) 🔲 🔏	Acknowledgment is made of a claim for	foreign priority und	er 35 U.S.C. § 119(a)	-(d) or (f).	
a)[☐ All b)				
•	1. ☐ Certified copies of the priority doc	uments have been	received.		
2	2. Certified copies of the priority doci	uments have been	received in Application	on No	
	 Copies of the certified copies of th application from the Internation ee the attached detailed Office action for 	nal Bureau (PCT R	ule 17.2(a)).	_	
14) 🗌 Ad	cknowledgment is made of a claim for do	omestic priority und	ler 35 U.S.C. § 119(e) (to a provisional applic	ation).
a)	☐ The translation of the foreign langua cknowledgment is made of a claim for de	ge provisional app	lication has been rece	eived.	,
ttachment(s)				
2) 🔲 Notice	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-9 ation Disclosure Statement(s) (PTO-1449) Paper I	48) 5	Interview Summary Notice of Informal Poly Other:	(PTO-413) Paper No(s) atent Application (PTO-152)	_·
Patent and Tra O-326 (Rev		ffice Action Summary		Part of Paper I	No. 5

DETAILED ACTION

1. This Office Action is in response to the Amendment filed September 23, 2002. Claims 1-12 are canceled.

Claims 13-24 are pending.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 13-24 are rejected under 35 U.S.C. 103(a) as being unpatentable over Pev et al. (U.S. 6,180,501) in view of McAnally et al. (U.S. 6,136,700).

Pey et al. teaches providing a semiconductor substrate having: a gate electrode (a pad oxide layer and a polysilicon layer) with gate spacers, shallow trench isolation regions, source and drain regions, and LDD regions (Fig. 1-7, col. 5, lines 1-60). Pey et al. discloses forming an etch stop material (silicon nitride) over the surface of the substrate and patterning the pad oxide layer, the polysilicon layer, and the etch stop material (Fig. 1-2, col. 5, lines 1-15).

Pey et al. teaches forming a salicide layer by depositing a Ti/TiN layer (280 to 350 angstroms) over the surface of the substrate, including the surface of the gate spacers, and performing a first RTP anneal (col. 5, lines 60-67, col. 6, lines 1-10). Pey et al. discloses creating a layer of titanium silicide over the surface of the source and

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drain regions, and removing the unreacted Ti/TiN layer (col. 6, lines 5-15). Pey et al. shows depositing a layer of dielectric (BPSG) over the surface of the layer of etch stop material, polishing the surface of the layer of dielectric down to the surface of the etch stop material, and removing the layer of etch stop material (col. 6, lines 23-50).

Pey et al. teaches depositing a Ti/TiN layer over the surface of the polished layer of dielectric including the exposed surface of the polysilicon layer and performing a second anneal (col. 7, lines 55-60). Furthermore, Pey et al. teaches creating reacted salicide material over the surface of polysilicon, removing the unreacted material, and performing a third RTP anneal at 850°C for about 10 to 30 seconds (col. 6, lines 5-15, col. 7, lines 55-60).

Pey et al. fails to show using a boronitride layer. However, McAnally et al. shows using a boronitride layer as a stopping layer in order to increase the etch selectivity (col. 3, lines 17-25, col. 4, lines 15-20, col. 5, lines 25-30).

Therefore, it would have been obvious to a person of ordinary skill in the art at the time of the invention to modify Pey et al.'s process by using boronitride instead of silicon nitride as taught McAnally et al. The modification would reduce the possibility of a short between the polysilicon and the subsequently formed silicide layer (McAnally et al., col. 5, lines 32-38).

Regarding the claimed thickness, temperature, and time, a particular parameter must first be recognized as a result-effective variable, i.e., a variable, which achieves a recognized result, before the determination of the optimum or workable ranges of, said variable might be characterized as routine experimentation. In re Aller, 220 F.2d 454,

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456, 105 USPQ 233, 235 (CCPA 1955). In re Geisler, 116 F.3d 1465, 1471, 43 USPQ2d 1362, 1366 (Fed. Cir. 1997).

Response to Arguments

3. Applicant's arguments filed September 23, 2002 have been fully considered but they are not persuasive. The objections to the Specification and claims are withdrawn. Claims 13-24 stand rejected.

In response to applicant's argument that the references fail to show certain features of applicant's invention, it is noted that the features upon which applicant relies (i.e., the polishing selectivity for photoresist/BN is larger than about 200) are not recited in the rejected claim(s). Although the claims are interpreted in light of the specification, limitations from the specification are not read into the claims. See *In re Van Geuns*, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993).

In response to applicant's argument that McAnally et al. uses the boron nitride as an etch stop layer, the test for obviousness is not whether the features of a secondary reference may be bodily incorporated into the structure of the primary reference; nor is it that the claimed invention must be expressly suggested in any one or all of the references. Rather, the test is what the combined teachings of the references would have suggested to those of ordinary skill in the art. See *In re Keller*, 642 F.2d 413, 208 USPQ 871 (CCPA 1981).

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Conclusion

4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Bartush (U.S. 5,365,866) teaches the use of a boron nitride polish stop layer as well known in the art. Stanley Wolf (of record) "Silicon Processing for the VLSI Era" teaches, as well known in the art, rapid thermal processing at 600-800°C to form a silicide layer, selectively removed the unreacted Ti, annealing the titanium silicide at temperature of 1000°C. for 30 seconds to reduce the titanium silicide resistivity (page 148).

5. **THIS ACTION IS MADE FINAL.** Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Maria Guerrero whose telephone number is 703-305-0162.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Amir Zarabian can be reached on 703-308-4905. The fax phone numbers for the organization where this application or proceeding is assigned are 703-308-7722 for regular communications and 703-308-7724 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

MG MG

November 19, 2002

AMIR ZARABIAN

SUPERVISORY PATENT EXAMINER

TECHNOLOGY CENTER 2800